Application/Control No: O9/000,008 Applicant(s)/Patent Under Reexamination PLOUG ET AL. Examiner Han Lieh Liu Art Unit Page 1 of 1

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Notice of References Cited

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Name | Classification |
|---|---|---|-----------------|--------------------|----------------|
| | А | US-5,086,689 | 02-1992 | Masuda, Kenji | 91/499 |
| - | В | US-4,815,358 | 03-1989 | Şmith, Richard H. | 92/12.2 |
| | С | US-3,657,970 | 04-1972 | Kobayashi et al. | 91/485 |
| | D | US-4,583,921 | 04-1986 | Wolff et al. | 417/269 |
| | Е | US-4,269,574 | 05-1981 | Bobier, Wilfred S. | 417/506 |
| | F | US-3,479,963 | 11-1969 | Randa et al. | 91/485 |
| | G | US-3,075,472 | 01-1963 | Garnier, George | 91/506 |
| | Н | US-3,046,906 | 07-1962 | Budzich, Tadensz | 91/487 |
| | ı | US- | | | |
| | J | US- | | | |
| | к | US- | | | |
| | L | US- | - | | |

U.S. PATENT DOCUMENTS

FOREIGN PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Country | Name | Classification |
|---|---|--|-----------------|---------|------|----------------|
| | N | | | | | |
| | 0 | | | | | |
| | Р | | | | | |
| | α | | | | | |
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| | S | | | | | |
| | Т | | | | | |

NON-PATENT DOCUMENTS

| * | | Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages) | |
|---|---|---|-------|
| | U | | |
| | V | | 3.9.5 |
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| | x | | |

A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.

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